Dual 4-line to 1-line multiplexer 74F153

FEATURES

- Non-inverting outputs
- Separate enable for each section
- Common select inputs
- See 74F253 for 3-State version

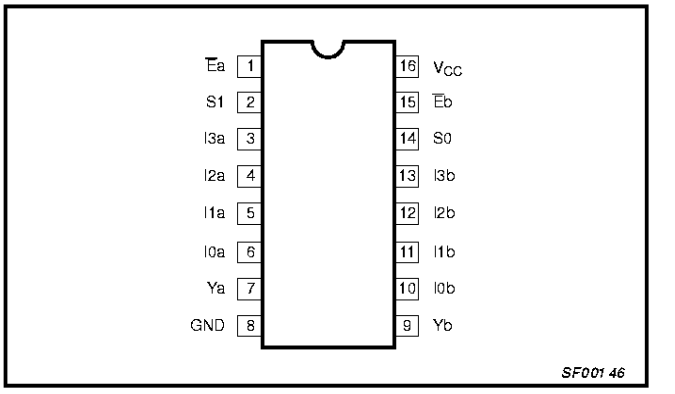
DESCRIPTION

The 74F153 is a dual 4-input multiplexer that can select 2 bits of data from up to four sources selected by common Select inputs (S0, S1). The two 4-input multiplexer circuits have individual active-Low Enables ($\overline{E}a$, $\overline{E}b$) which can be used to strobe the outputs independently. Outputs (Ya, Yb) are forced Low when the corresponding Enables ($\overline{E}a$, $\overline{E}b$) are High.

The 74F153 is the logic implementation of a 2-pole, 4-position switch where the switch is determined by the logic levels supplied to the common select inputs.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F153	7.0ns	12mA

PIN CONFIGURATION



ORDERING INFORMATION

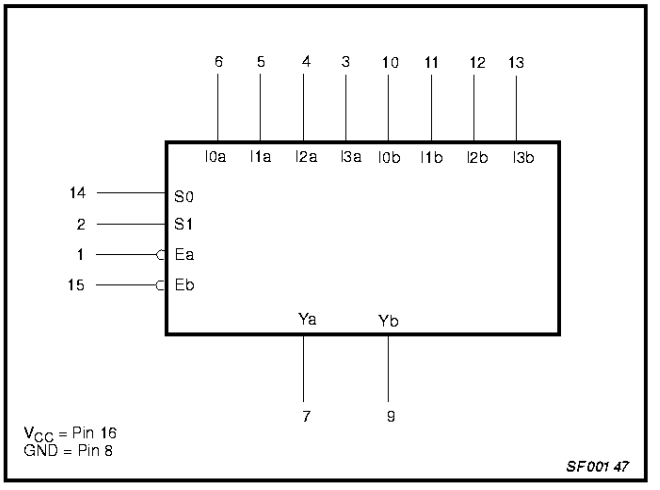
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	PKG. DWG. #
16-pin plastic DIP	N74F153N	SOT38-4
16-pin plastic SO	N74F153D	SOT162-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

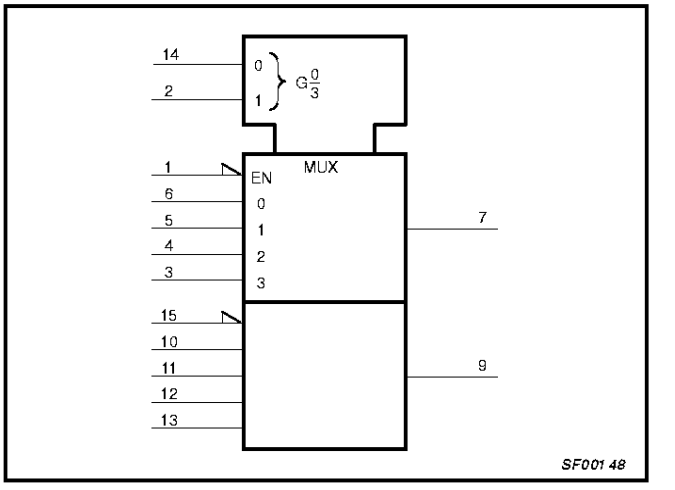
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
I0a – I3a	Port A data inputs	1.0/1.0	20µA/0.6mA
I0b – I3b	Port B data inputs	1.0/1.0	20µA/0.6mA
S0, S1	Common Select inputs	1.0/1.0	20µA/0.6mA
$\overline{E}a$	Port A Enable input (active Low)	1.0/1.0	20µA/0.6mA
$\overline{E}b$	Port B Enable input (active Low)	1.0/1.0	20µA/0.6mA
Ya, Yb	Port A, B data outputs	50/33	1.0µA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

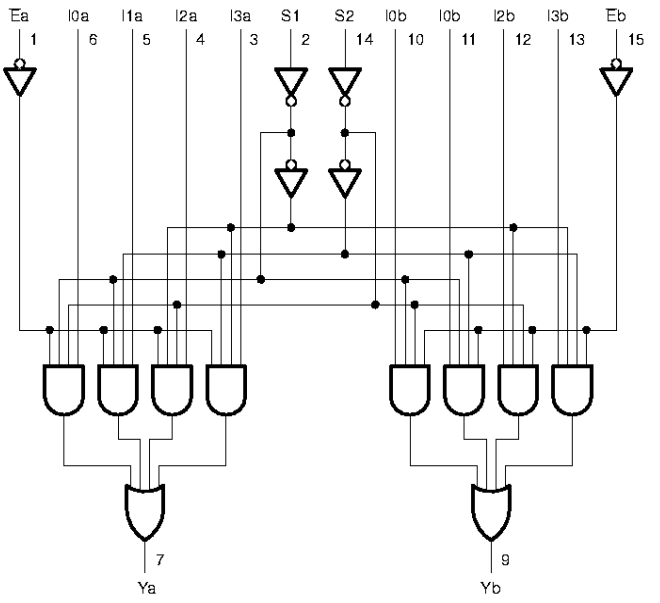
LOGIC SYMBOL



IEC/IEEE SYMBOL



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS							OUTPUT
S0	S1	$\overline{En}$	I0n	I1n	I2n	I3n	Yn
X	X	H	X	X	X	X	L
L	L	L	L	X	X	X	L
L	L	L	H	X	X	X	H
H	L	L	X	L	X	X	L
H	L	L	X	H	X	X	H
L	H	L	X	X	L	X	L
L	H	L	X	X	H	X	H
H	H	L	X	X	X	L	L
H	H	L	X	X	X	H	H

H = High voltage level
L = Low voltage level
X = Don't care

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	−0.5 to +7.0	V
V_{IN}	Input voltage	−0.5 to +7.0	V
I_{IN}	Input current	−30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	−0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state	40	mA
T_{amb}	Operating free-air temperature range	0 to +70	°C
T_{stg}	Storage temperature range	−65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			−18	mA
I_{OH}	High-level output current			−1	mA
I_{OL}	Low-level output current			20	mA
T_{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS[1]		LIMITS			UNIT
					MIN	TYP[2]	MAX	
V_{OH}	High-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}	2.5			V
			V_{IH} = MIN, I_{OH} = MAX	±5%V_{CC}	2.7	3.4		
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IL} = MAX	±10%V_{CC}		0.30	0.50	V
			V_{IH} = MIN, I_{OL} = MAX	±5%V_{CC}		0.30	0.50	
V_{IK}	Input clamp voltage		V_{CC} = MIN, I_I = I_{IK}			−0.73	−1.2	V
I_I	Input current at maximum input voltage		V_{CC} = MAX, V_I = 7.0V				100	µA
I_{IH}	High-level input current		V_{CC} = MAX, V_I = 2.7V				20	µA
I_{IL}	Low-level input current		V_{CC} = MAX, V_I = 0.5V				−0.6	mA
I_{OS}	Short-circuit output current[3]		V_{CC} = MAX		−60		−150	mA
I_{CC}	Supply current (total)	I_{CCH}	V_{CC} = MAX	$\overline{En}$ = GND, Sn=In=4.5V		12	20	mA
		I_{CCL}		En=Sn=In=GND		12	20	mA

NOTES:

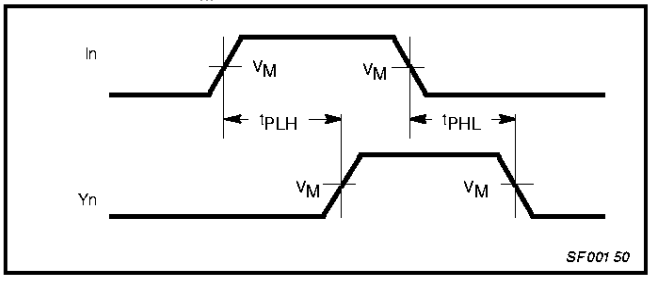
1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

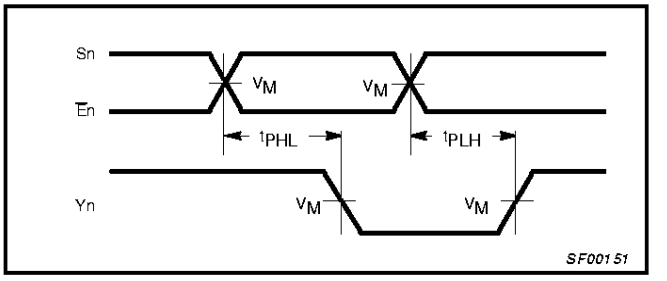
SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			V_{CC} = +5.0V T_{amb} = +25°C C_L = 50pF, R_L = 500Ω			V_{CC} = +5.0V ± 10% T_{amb} = 0°C to +70°C C_L = 50pF, R_L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	
t_{PLH} t_{PHL}	Propagation delay In to Yn	Waveform 1	3.0 3.0	4.5 5.0	7.0 7.5	2.5 2.5	8.0 8.0	ns
t_{PLH} t_{PHL}	Propagation delay Sn to Yn	Waveform 2	5.0 5.0	8.0 8.0	10.5 10.5	4.5 4.5	12.0 12.0	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{En}$ to Yn	Waveform 2	5.0 4.0	7.5 5.5	9.0 7.0	4.5 3.5	10.5 8.0	ns

AC WAVEFORMS

For all waveforms, V_M = 1.5V.

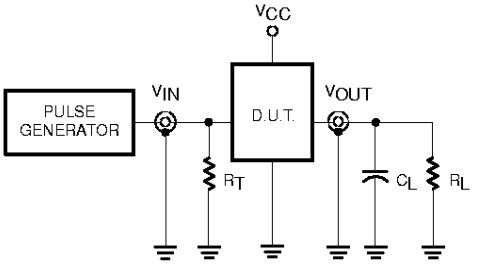


Waveform 1. Propagation Delay, Data to Output

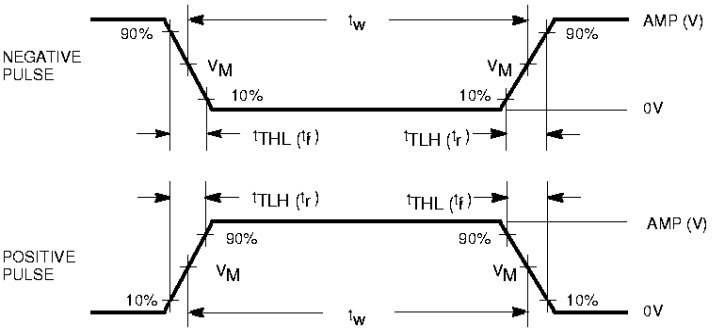


Waveform 2. Propagation Delay, Enable and Select to Output

TEST CIRCUIT AND WAVEFORMS



Test Circuit for Totem-Pole Outputs



DEFINITIONS:

R_L = Load resistor; see AC ELECTRICAL CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

Input Pulse Definition

family	INPUT PULSE REQUIREMENTS					
	amplitude	V_M	rep. rate	t_w	t_{TLH}	t_{THL}
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

SF00006